

**Search Notes**

Application/Control No.

10/620,594

Examiner

SETH WEIS

Applicant(s)/Patent under  
Reexamination

SAKAI ET AL.

Art Unit

3695

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (attached)	11/24/2008	SW